

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/511,862	WASHAKOWSKI ET AL.	
Examiner		Art Unit		Page 1 of 3
Leon-Viet Q. Nguyen		2635		

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		10/511,862	WASHAKOWSKI ET AL.	
Examiner		Art Unit		Page 2 of 3
Leon-Viet Q. Nguyen		2635		

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	10/511,862	WASHAKOWSKI ET AL.	
	Examiner Leon-Viet Q. Nguyen	Art Unit 2635	Page 3 of 3

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	F	US-			
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	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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